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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/541,961	HART ET AL.	
Examiner	Art Unit	
Lindsey Bachman	3734	

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Class	Subclass	Date	Examiner
606	157, 158		
606	151		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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